

Search Notes

Application No.

10/622,466

Examiner

Stephen W. Smoot

Applicant(s)

NA ET AL.

Art Unit

2813

SEARCHED

Class	Subclass	Date	Examiner
438	458	7/24/2004	SWS
438	459	7/24/2004	SWS
438	463	7/24/2004	SWS
438	479	7/24/2004	SWS
438	940	7/24/2004	SWS
438	977	7/24/2004	SWS

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Key Words: Gallium Nitride - GaN; Growth Substrate - Sapphire, Silicon Carbide, SiC;	7/24/2004	<i>S.W.S.</i> SWS
Laser - Ablate, Remove, separate.	7/24/2004	<i>S.W.S.</i> SWS
Search Tools - EAST (attached): USPAT; US PG PUBS; Derwent; EPO; JPO; IBM TDB	7/24/2004	<i>S.W.S.</i> SWS